U.S. Pat. Appl. Ser. No. 10/552,395 Attorney Docket No. 10191/4259 Reply to Office Action of February 9, 2009

## **Amendments to the Claims:**

This listing of claims will replace all prior versions, and listings, of claims in the application:

## **Listing of Claims:**

1-9. (Canceled).

10. (Currently Amended) A [[The]] method according to claim 9 for determining a control voltage of a piezoelectric element, further comprising:

sensing a voltage drop at the piezoelectric element after a charge process, the sensing of the voltage drop including:

measuring a first voltage applied at the piezoelectric element immediately following the charge process;

measuring a second voltage applied at the piezoelectric element immediately prior to a subsequent discharge process; and

subtracting the first and second applied voltages from each other to provide a difference; [[,]] and

<u>determining</u> the <u>individual</u> control voltage of the piezoelectric element <del>being inferred</del> from the difference.

11. (Currently Amended) The method according to claim 10, wherein further comprising gathering the individual control voltage is obtained from a characteristic curve which represents representing a relationship relation between the difference and the individual control voltage.

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12. (Currently Amended) A [[The]] method according to claim 11 for ascertaining a control voltage of a piezoelectric element, the method further comprising:

measuring a first voltage applied at the piezoelectric element following a charge process;

measuring a second voltage applied at the piezoelectric element prior to a subsequent discharge process;

subtracting the first and second applied voltages from each other to provide a difference;

inferring the control voltage of the piezoelectric element from the difference, wherein the control voltage is inferred from a characteristic representing a relation between the difference and the control voltage; and

ascertaining the characteristic experimentally on the basis of a large number of measurements at different actuators.

13. (Currently Amended) A [[The]] method according to claim 9 for ascertaining an individual control voltage of a piezoelectric element, the method further comprising:

measuring a voltage drop at the piezoelectric element following a charge process; increasing the voltage applied at the piezoelectric element during the charge process iteratively until a voltage applied at the piezoelectric element immediately following the charge process does not deviate from a voltage applied at the piezoelectric element immediately prior to a subsequent discharge process; and

rating the voltage as an individual voltage requirement, from which the individual control voltage of the piezoelectric element is inferred.

- 14. (Currently Amended) The method according to claim 13, wherein the iterative increase of the voltage applied to the piezoelectric element and the measurement of the voltage able to be tapped off at the piezoelectric element are conducted at low pressures of a fluid to be injected.
- 15. (Previously Presented) The method according to claim 13, further comprising continuously measuring a voltage characteristic at the piezoelectric element.

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16. (Currently Amended) A [[The]] method according to claim 9 for ascertaining a control voltage of a piezoelectric element, the method further comprising:

measuring a voltage drop at the piezoelectric element following a charge process; inferring the control voltage of the piezoelectric element from the voltage drop; applying only one voltage to the piezoelectric element; and

increasing a charge time iteratively until a voltage applied at the piezoelectric element immediately following the charge process does not deviate from a voltage applied at the piezoelectric element immediately prior to a subsequent discharge process.

- 17. (New) The method according to claim 16, further comprising continuously measuring a voltage characteristic at the piezoelectric element.
- 18. (New) The method according to claim 14, further comprising continuously measuring a voltage characteristic at the piezoelectric element.
- 19. (New) A method for ascertaining a control voltage of a piezoelectric element, the method comprising:

measuring a voltage drop at the piezoelectric element following a charge process; applying only one voltage to the piezoelectric element; and

inferring the control voltage of the piezoelectric element by increasing a charge time iteratively until a voltage applied at the piezoelectric element immediately following the charge process does not deviate from a voltage applied at the piezoelectric element immediately prior to a subsequent discharge process.

- 20. (New) The method according to claim 19, further comprising continuously measuring a voltage characteristic at the piezoelectric element.
- 21. (New) The method according to claim 11, wherein the relationship provides that, for a rise in the difference, there is a rise in the control voltage.

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